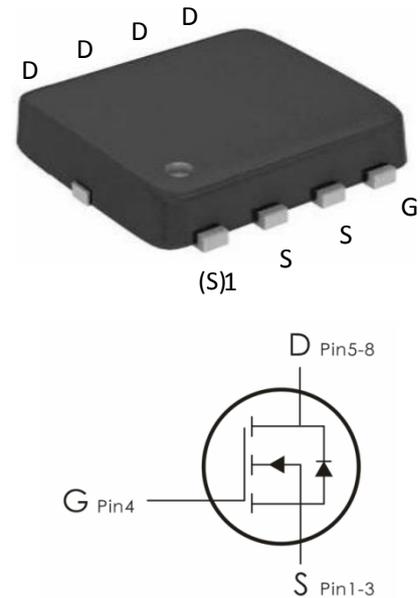


## Description:

This N-Channel MOSFET uses advanced trench technology to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

## Features:

- 1)  $V_{DS}=30V, I_D=90A, R_{DS(ON)} < 4.2m\ \Omega @ V_{GS}=10V$
- 2) Improved dv/dt capability
- 3) Fast switching
- 4) 100% EAS Guaranteed
- 5) Green Device Available.



## Absolute Maximum Ratings: ( $T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Ratings	Units
$V_{DS}$	Drain-Source Voltage	30	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D$	Continuous Drain Current-Continuous ( $T_C=25^\circ C$ )	90	A
	Continuous Drain Current- $T_C=100^\circ C$	53	
$I_{DM}$	Drain Current – Pulsed <sup>1</sup>	330	A
$E_{AS}$	Single Pulse Avalanche Energy	240	mJ
$P_D$	Power Dissipation ( $T_C=25^\circ C$ )	45	W
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to +150	$^\circ C$

## Thermal Characteristics:

Symbol	Parameter	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.5	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient <sup>3</sup>	62.5	

## Package Marking and Ordering Information:

Part NO.	Marking	Package
ZC005NG	C005N	DFN3*3-8

## Electrical Characteristics: ( $T_C=25^\circ\text{C}$ unless otherwise noted)

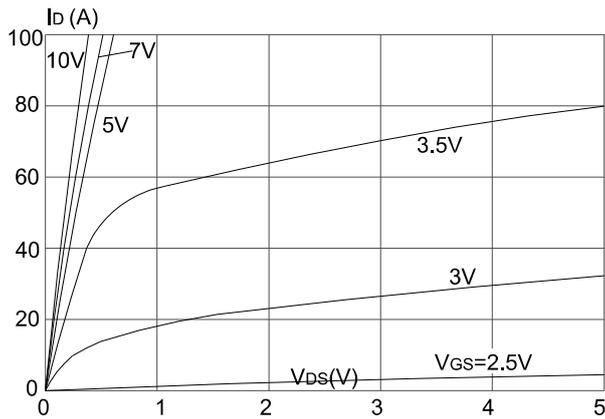
Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\ \mu\text{A}$	30	---	---	V
$I_{DSS}$	Drain-Source Leakage Current	$V_{GS}=0V, V_{DS}=24V, T_J=25^\circ\text{C}$	---	---	10	$\mu\text{A}$
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0A$	---	---	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(th)}$	GATE-Source Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\ \mu\text{A}$	1	1.5	3	V
$R_{DS(on)}$	Drain-Source On Resistance <sup>2</sup>	$V_{GS}=10V, I_D=30A$	---	3.6	4.2	m $\Omega$
		$V_{GS}=4.5V, I_D=20A$	---	---	7	
$G_{FS}$	Forward Transconductance	$V_{DS}=5V, I_D=6A$	---	13	---	S
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS}=25V, V_{GS}=0V, f=1\text{MHz}$	---	1950	2350	pF
$C_{oss}$	Output Capacitance		---	320	---	
$C_{rss}$	Reverse Transfer Capacitance		---	240	---	
$R_g$	Gate Resistance	$f=1\text{MHz}$	---	0.9	---	$\Omega$
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD}=15V, V_{GS}=10V, R_G=3.3\ \Omega, I_D=15A$	---	13	---	ns
$t_r$	Rise Time		---	36	---	ns
$t_{d(off)}$	Turn-Off Delay Time		---	43	---	ns
$t_f$	Fall Time		---	16	---	ns
$Q_g$	Total Gate Charge	$V_{DS}=24V, V_{GS}=10V, I_D=20A$	---	42	---	nC
$Q_{gs}$	Gate-Source Charge		---	3.9	---	nC
$Q_{gd}$	Gate-Drain "Miller" Charge		---	14	---	nC
<b>Drain-Source Diode Characteristics</b>						

<b>V<sub>SD</sub></b>	Source-Drain Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V, I <sub>S</sub> =30A, T <sub>J</sub> =25°C	---	---	1.2	V
<b>t<sub>rr</sub></b>	Reverse Recovery Time	V <sub>GS</sub> =0V, I <sub>S</sub> =10A, di/dt=100A	---	16	---	nS
<b>Q<sub>rr</sub></b>	Reverse Recovery Charge		---	5	---	nC

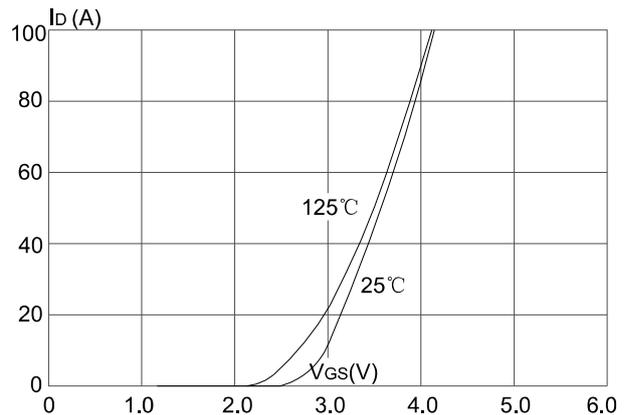
**Notes:**

1. Pulse width limited by max. junction temperature
2. Pulse test
3. Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board

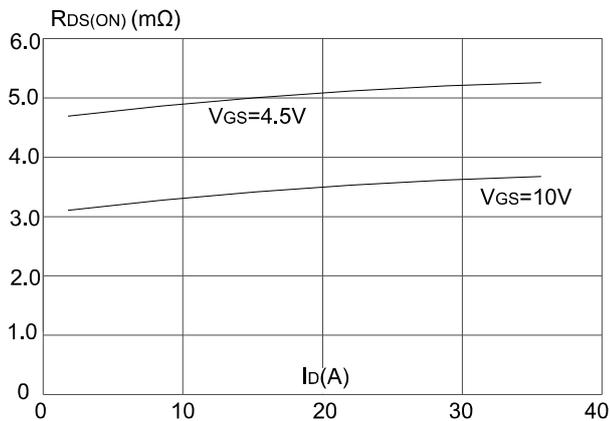
**Typical Characteristics:** (T<sub>C</sub>=25°C unless otherwise noted)



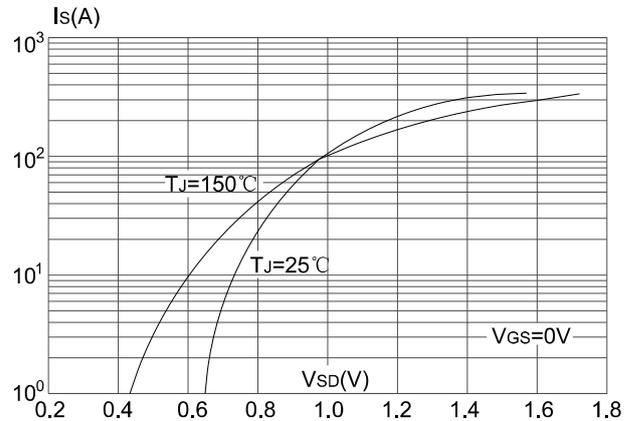
**Figure 1: Output Characteristics**



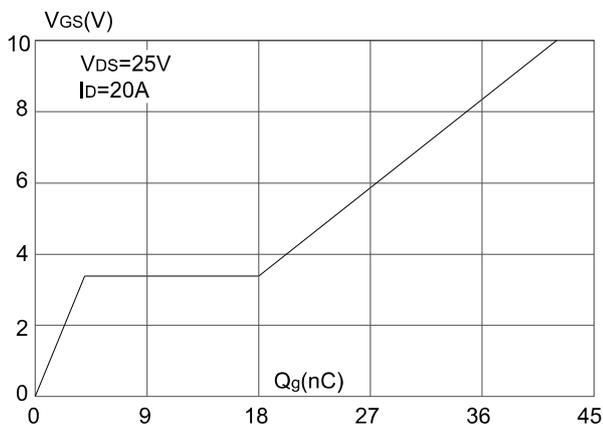
**Figure 2: Typical Transfer Characteristics**



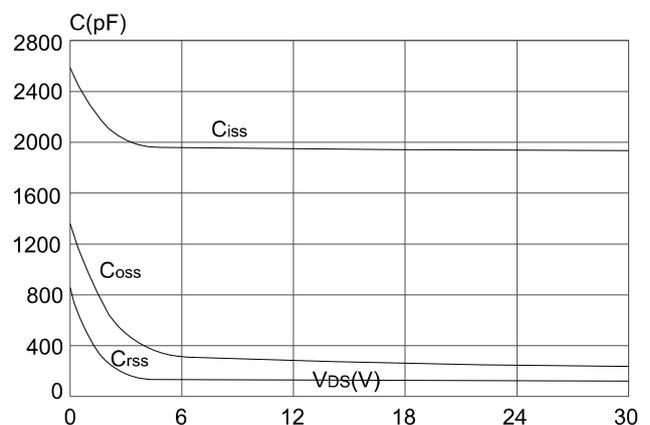
**Figure 3: On-resistance vs Drain Current**



**Figure 4: Body Diode Characteristics**

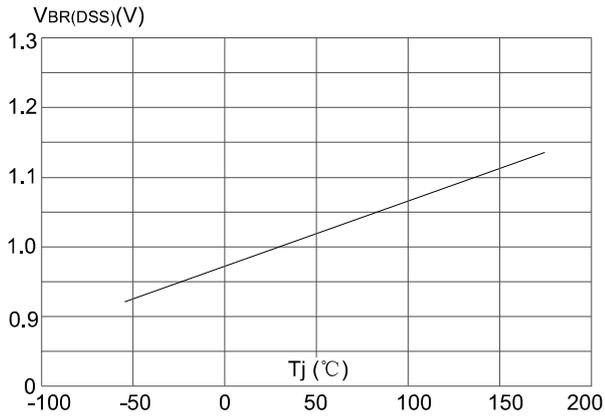


**Figure 5: Gate Charge Characteristics**



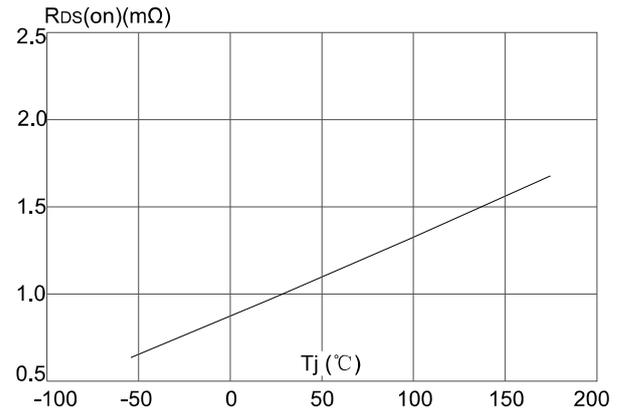
**Figure 6: Capacitance Characteristics**

Junction Temperature

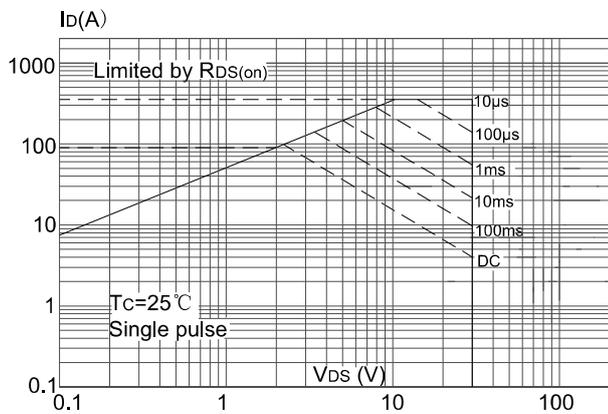


**Figure 7:** Normalized Breakdown Voltage vs.

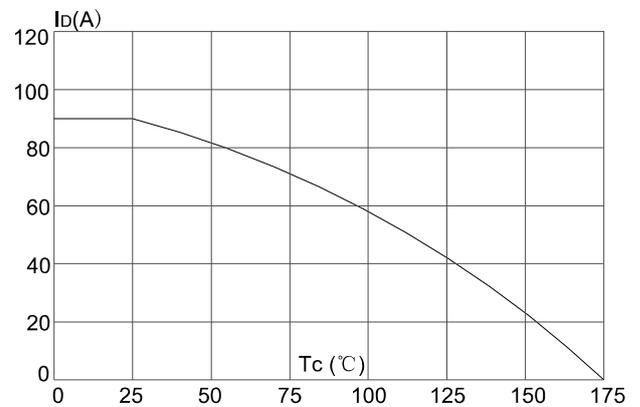
Junction Temperature



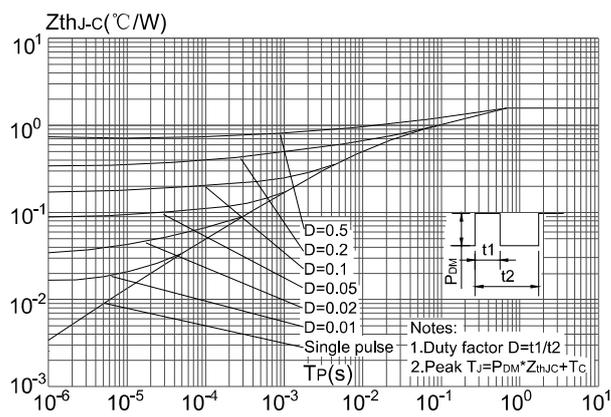
**Figure 8:** Normalized on Resistance vs.



**Figure 9:** Maximum Safe Operating Area



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



**Figure.11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case